



## 18. TEST PHOTOGRAPHS

See following Attached Pages for setup photographs.

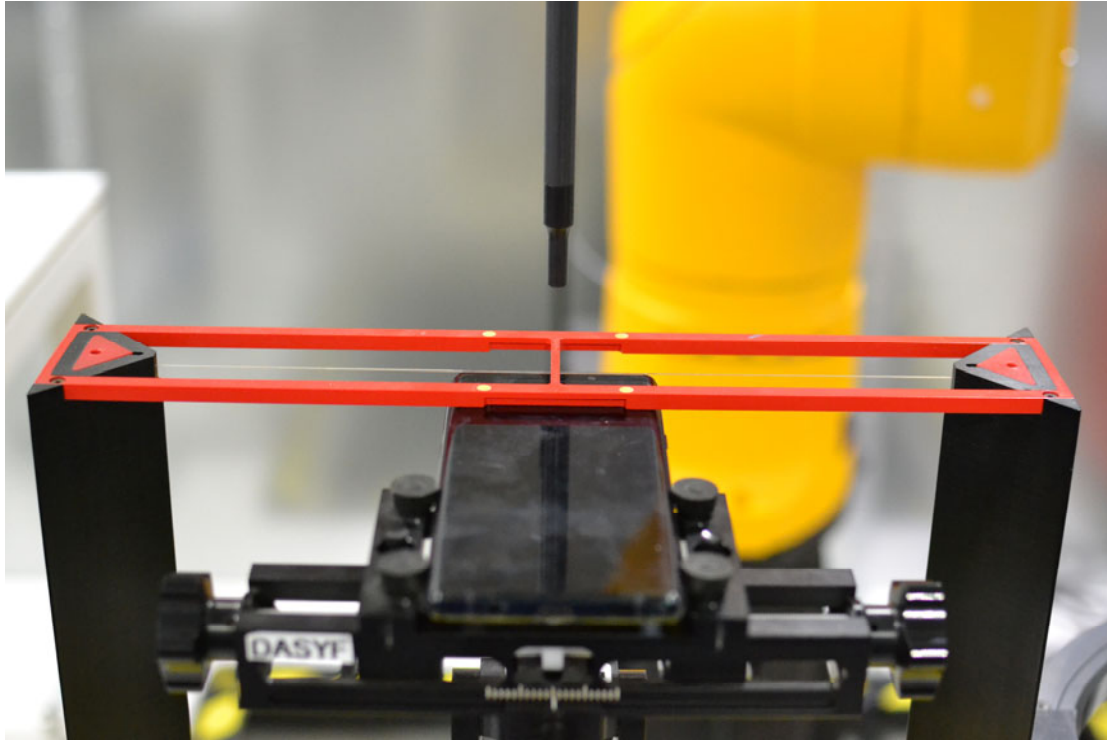
<b>FCC ID:</b> A3LSMN960U	 <b>PCTEST</b> ENGINEERING LABORATORY, INC.	<b>HAC (RF EMISSIONS) TEST REPORT</b>		<b>Approved by:</b> Quality Manager
<b>Filename:</b> 1M1806290138-03.A3L	<b>Test Dates:</b> 07/02/2018 - 07/04/2018	<b>DUT Type:</b> Portable Handset	Page 51 of 53	

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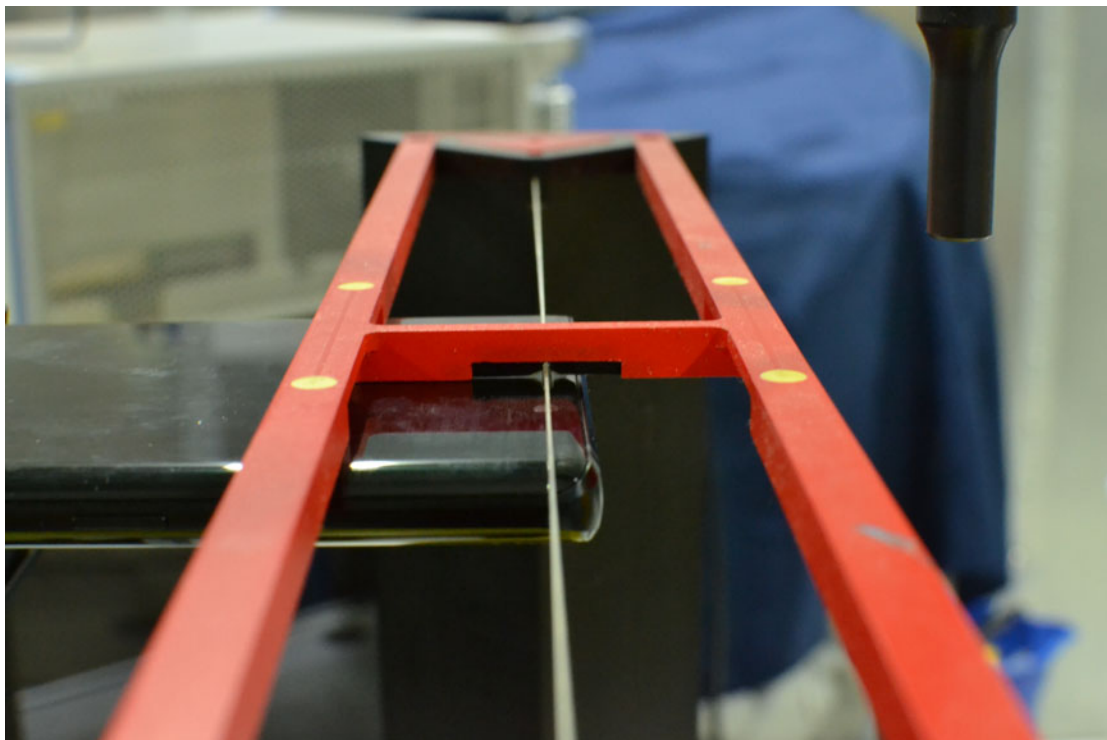
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04/17/2018



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**Figure 18-1**  
**Ear Reference Point HAC Phantom Alignment**



**Figure 18-2**  
**HAC Phantom Plane Alignment**

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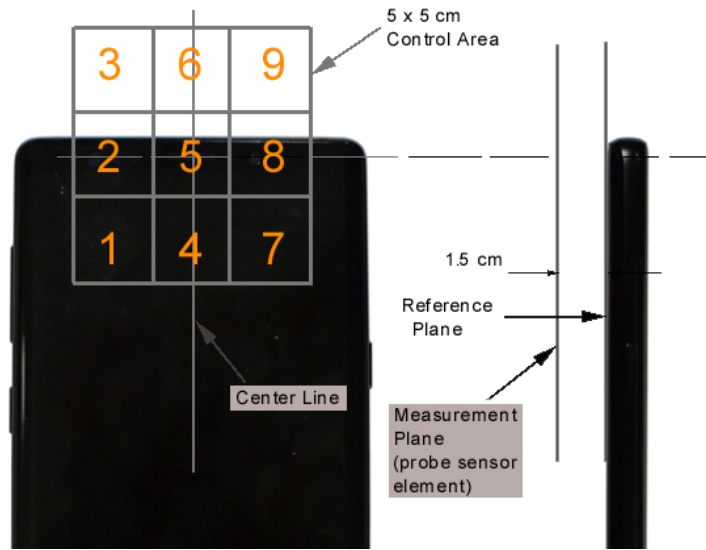




Figure 18-3 5x5 Scan grid above WD



Figure 18-4 E-Field WD Scan overlay

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